

Notice of References Cited	Application/Control No. 10/091,204	Applicant(s)/Patent Under Reexamination ONG ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2005/0240640	10-2005	Kaler et al.	707/205
*	B	US-2004/0205452	10-2004	Fitzsimons et al.	715/500
*	C	US-2003/0018834	01-2003	Eilers et al.	710/1
*	D	US-2002/0046262	04-2002	Heilig et al.	709/219
*	E	US-6,993,476	01-2006	Dutta et al.	704/9
*	F	US-6,922,824	07-2005	Swetland, Brian	717/117
*	G	US-6,915,507	07-2005	Kaler et al.	717/103
*	H	US-6,886,034	04-2005	Blumberg, Robert	709/217
*	I	US-6,842,904	01-2005	Bartz et al.	719/328
*	J	US-6,721,804	04-2004	Rubin et al.	709/246
*	K	US-6,615,212	09-2003	Dutta et al.	707/10
*	L	US-6,295,541	09-2001	Bodnar et al.	707/203
*	M	US-6,249,794	06-2001	Raman, T. V.	715/500

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	X	

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